


<b>Search Notes</b>  	<b>Application/Control No.</b>  10590534	<b>Applicant(s)/Patent Under Reexamination</b>  BIEN ET AL.
	<b>Examiner</b>  Mark H Paschall	<b>Art Unit</b>  3742

SEARCHED			
Class	Subclass	Date	Examiner
219	121..45, 121.46, 121.59, 127,125.1, 137R		
126	116R	6-30-2010	mhp

SEARCH NOTES		
Search Notes	Date	Examiner
east search enclosed.	6-30-2010	mhp

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

	/Mark H Paschall/ Primary Examiner.Art Unit 3742
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